

**Search Notes**

Application/Control No.

10/629,624

Examiner

Anthony Fick

Applicant(s)/Patent under  
Reexamination

SHUTOH ET AL.

Art Unit

1753

**SEARCHED**

Class	Subclass	Date	Examiner
136	203	1/9/2007	ADF
136	200-242	1/9/2007	ADF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search history	1/9/2007	ADF
Inventor search	1/9/2007	ADF
Consulted with Nam Nguyen	1/9/2007	ADF
Google scholar search for inventor and keywords	1/9/2007	ADF